

Claim 20 (Amended)

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The microscope assemblage as defined in Claim 12, characterized in that the second optical reference point is at a center of an objective pupil (9).

Claim 21 (Amended)

The method as defined in Claim 12, characterized in that all optical elements are alignable with respect to the reference points.

Claim 27 (Amended)

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The microscope assemblage as defined in Claim 13, characterized in that the illuminating light beam is rotated or tilted about the illumination stop (3).  
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Remarks

The Section 112 Rejection of Claims 1-27

The Examiner rejected Claims 1-27 under 35 U.S.C. §112, second paragraph, as being indefinite for failing to particularly point out and distinctly claim the subject matter which the applicant regards as the invention. To the extent that the rejection may apply to the amended claims, applicant respectfully traverses this rejection and requests reconsideration.

Claim 1 has been amended to correct the lack of antecedent basis for the phrase "the two reference points." Claim 1 has also been amended to remove the phrase "or in two planes." Applicant believes amended Claim 1 is now in condition for allowance.

Applicant believes Claim 3 is now clear due to the removal of the phrase "or in two planes" from Claim 1.

Claims 5 and 20 have been amended to clarify that the reference point is the center of an objective pupil. Applicant believes amended Claims 5 and 20 are now in condition for allowance.

Claim 12 has been amended to remove the phrase “or in two planes” and to clarify the definition of the two reference planes. Applicant believes the claim is now clear, as two reference points define a beam path. Further, applicant believes the phrase “microscope optical system” is clear as it is known in the art as referring to a system that includes, for example, a light source, illumination and detection path lenses, and an objective lens and its entrance pupil.

Claim 27 has been amended to depend from Claim 13 rather than Claim 26, to clarify what is being added to the base claim. Applicant believes amended Claim 27 is now in condition for allowance.

In view of these amendments, reconsideration of the rejection is respectfully requested.

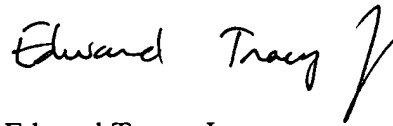
#### New Claims

Claims 28-31 have been added to claim the method of the present invention using reference planes. This matter was previously included in the original Claims 1 and 12. Entry into the present application in a favorable light is courteously requested.

Conclusion

For all of the reasons outlined above, Applicant respectfully submits that all pending claims are patentable and in condition for allowance, which action is courteously requested.

Respectfully submitted,

A handwritten signature in black ink that reads "Edward Tracy Jr." with a stylized flourish at the end.

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EWT  
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## **MARKED VERSION OF AMENDED CLAIMS**

1. A method for aligning the optical beam path of a microscope, having a light source (1), a microscope optical system, a detection stop (12), and a detection device (13), wherein the method comprises the steps of:

- a) providing a center of the detection stop (12) as a first optical reference point; and
- b) providing a second optical reference point wherein [the] an entire beam path is defined [at the two reference points or in two planes] by said first optical reference point and said second optical reference point.

4. The method as defined in Claim [1] 28, characterized in that the planes are Fourier planes.

5. The method as defined in Claim 1, characterized in that the second reference point is at a center of an objective pupil (9).

6. The method as defined in Claim 1, characterized in that all optical elements are aligned with respect to the reference points [or planes].

12. A microscope assemblage, having a light source (1), a microscope optical system, a detection device (13), a detection stop (12) defining a first optical reference point and a second optical reference point wherein [that the] an entire beam path is defined [at the two reference points or in two planes] by said first optical reference point and said second optical reference point.

19. The method as defined in Claim [18] 30, characterized in that the planes are Fourier planes.

20. The microscope assemblage as defined in Claim 12, characterized in that [in addition to the detection stop (12), an objective pupil (9) serves as a reference point] the second optical reference point is at a center of an objective pupil (9).

21. The method as defined in Claim 12, characterized in that all optical elements are alignable with respect to the reference points [or planes].

27. The microscope assemblage as defined in Claim [26] 13, characterized in that the illuminating light beam is rotated or tilted about the illumination stop (3).